

<b>Notice of References Cited</b>	Application/Control No. 09/786,102	Applicant(s)/Patent Under Reexamination STEK ET AL.	
	Examiner Esaw T. Abraham	Art Unit 2133	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,353,890	03-2002	Newman, Peter A.	713/193
*	B	US-6,081,651	06-2000	Kim, Jong Nam	386/111
*	C	US-6,216,201	04-2001	Ado et al.	711/112
*	D	US-6,115,227	09-2000	Jones et al.	361/119
*	E	US-5,995,460	11-1999	Takagi et al.	369/53.18
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.